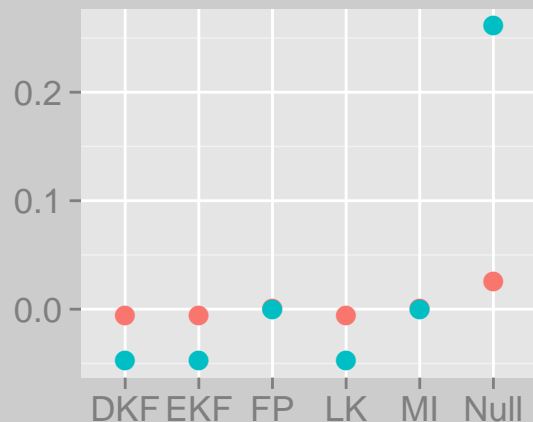
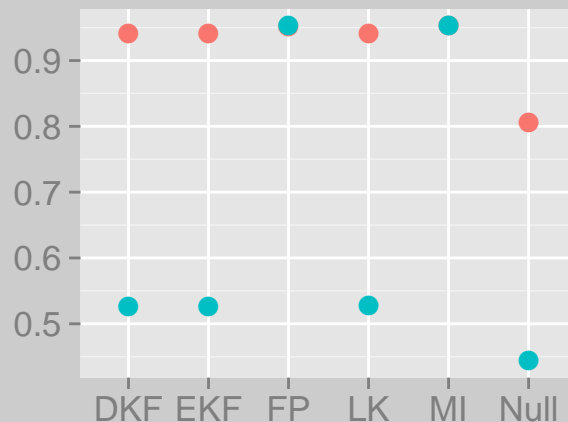


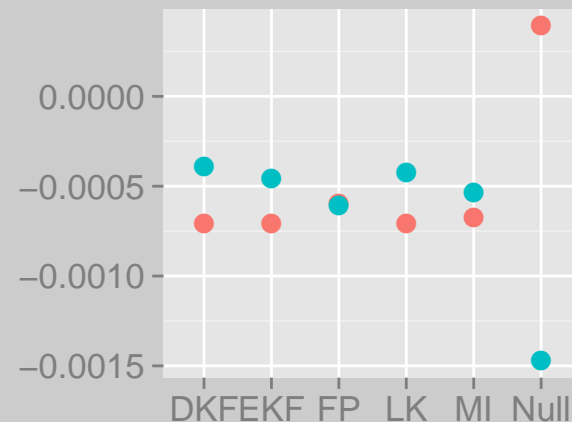
Bias
Measurement



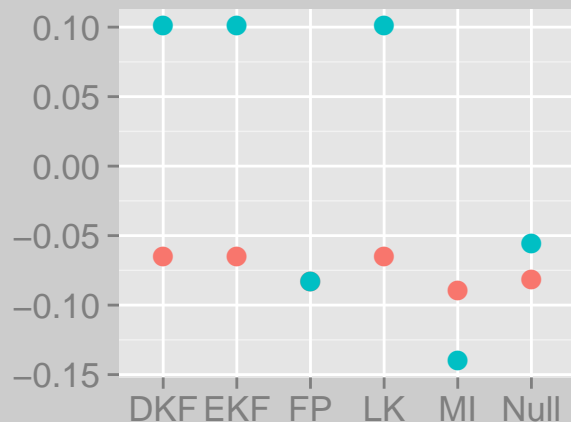
Coverage Rates
Measurement



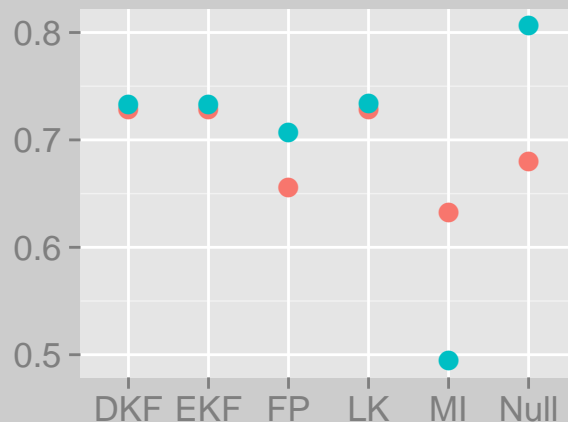
SD - SE
Measurement



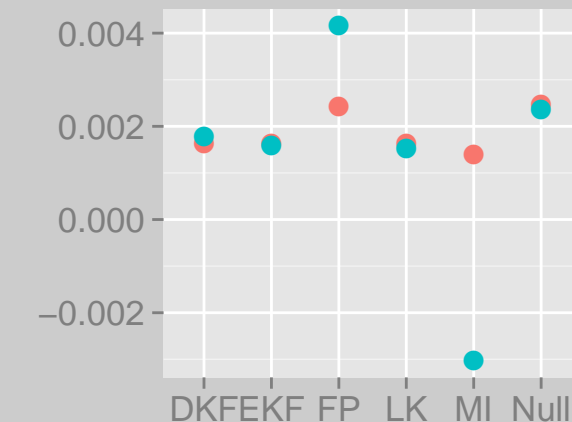
Process Noise



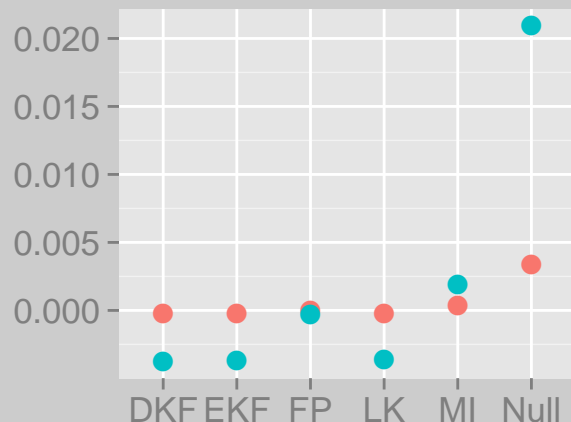
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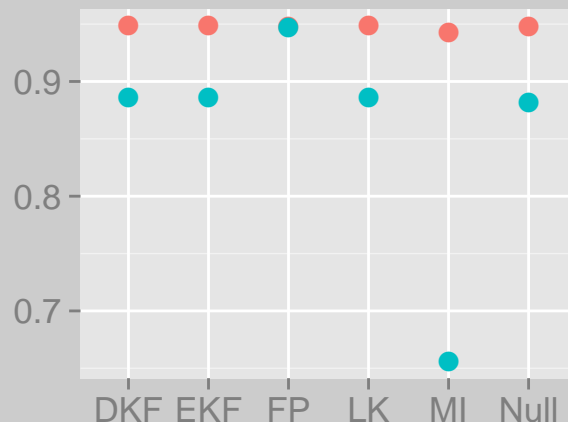
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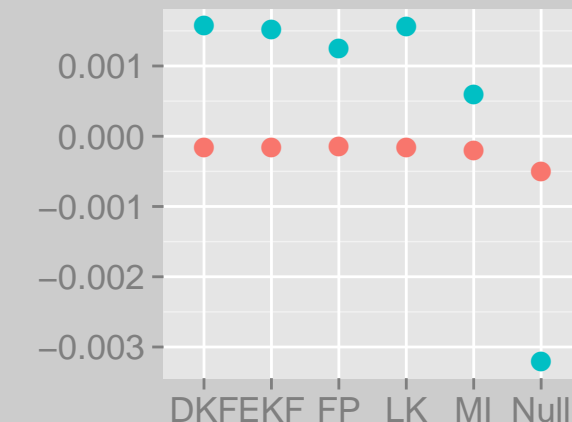
Time Series



Time Series



Time Series



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